

O I P E
SEP 26 2006

Express Mail Label No. EV620762918US

Under the Paperwork Reduction Act of 1995, no persons are required to respond to a collection of information unless it contains a valid OMB control number.

PTO/SB/08a/b (08-03)

Approved for use through 07/31/2006. OMB 0651-0031

U.S. Patent and Trademark Office; U.S. DEPARTMENT OF COMMERCE

Substitute for form 1449A/B/PTO

Complete If Known**INFORMATION DISCLOSURE STATEMENT BY APPLICANT**

(Use as many sheets as necessary)

Sheet 1 of 2 Attorney Docket Number ELM-2 Cont. 4

U.S. PATENT DOCUMENTS

Examiner Initials*	Cite No.*	Document Number Number-Kind Code* (# known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
MU		US 3,636,358	01/18/1972	Groschwitz	
		US 3,932,932	01/20/1976	Goodman	
		US 4,028,547	06/07/1977	Eisenberger	
		US 4,393,127	07/12/1983	Greschner et al.	
		US 4,528,072	07/09/1985	Kuroswa et al.	
		US 4,566,037	01/21/1986	Takatsu et al.	
		US 4,622,632	11/11/1986	Tanimoto et al.	
		US 4,810,889	03/07/1989	Yokomatsu et al.	
		US 5,051,326	09/24/1991	Celler et al.	
		US 5,062,689	11/05/1991	Koehler	
		US 5,117,282	05/26/1992	Salatino	
		US 5,166,962	11/24/1992	Murooka et al.	
		US 5,169,805	12/08/1992	Mok et al.	
		US 5,188,706	02/23/1993	Hori et al.	
		US 5,245,277	09/14/1993	Furtek et al.	
		US 5,283,107	02/01/1994	Bayer et al.	
		US 5,293,457	03/08/1994	Anme et al.	
		US 5,399,505	03/21/1995	Dasse et al.	
		US 5,432,996	07/18/1995	Capps et al.	
		US 5,450,603	09/12/1995	Davies	
		US 5,517,457	05/14/1996	Sakui et al.	
		US 5,572,689	11/05/1996	Gallup et al.	
		US 6,017,858	01/25/2000	Rhee et al.	
		US 6,092,174	07/18/2000	Roussakov	
		US 6,154,809	11/28/2000	Ikenaga et al.	
		US 6,300,935	10/09/2001	Sobel et al.	
		US 6,301,653	10/09/2001	Mohamed et al.	
		US 6,320,593	11/20/2001	Sobel et al.	
		US 6,355,876	03/12/2002	Fantis	
		US 2005-0023656	02/03/2005	Leedy	
MU		US 6,894,392	05/17/2005	Gudezen et al.	

FOREIGN PATENT DOCUMENTS

Examiner Initials*	Cite No.*	Foreign Patent Document Country Code*-Number*-Kind Code* (# known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	T#
		DE2235195	03-17-1983	Mitsubishi Electric Corp.		
		JP2037655	02-07-1990	Siemens AG		
		JP3127818	05-30-1991	Canon KK		
		JP3174745	07-29-1991	Fujitsu Limited		
		WO 98/10337	09-07-1998	Trust Technologies, LLC		

/TD/ 03/17/10

Examiner Signature *call* Date Considered *11/10/07*

Substitute for form 1449A/B/PTO				Complete If Known	
				Application Number	10/672,961 (Conf. No. 9439)
				Filing Date	September 26, 2003
				First Named Inventor	Glenn J. Leedy
				Art Unit	2822
				Examiner Name	Monica Lewis
Sheet	2	of	2	Attorney Docket Number	ELM-2 Cont. 4

NON PATENT LITERATURE DOCUMENTS						
Examiner Initials	Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.				T ²
		Wolf, Stanley and Richard N. Tauber; <u>Silicon Processing For the VLSI Era, Volume 1: Process Technology</u> ; Sunset Beach, CA: Lattice Press, 1986, pages 191-194				
		European Search Report for Application No. EP 02-00-9643 (date completed: October 8, 2002)				
		Phys. Rev. B, Condens. Matter Mater. Phys. (USA), Physical Review B (Condensed Matter and Materials Physics), 15 March 2003, APS through AIP, USA.				
		S. Wolf, <u>Silicon Processing For the VLSI Era</u> , 1990, Lattice Press, Volume 2, page 191.				
		Svechnikov, S.V.; Kobylavtksaya, M.F.; Kimarskii, V.I.; Kaufman, A.P.; Kuzolev, Yu. I.; Cherepov, Ye. I.; Fomin, B.I.; "A switching plate with aluminium membrane crossings of conductors"; 1972				
		Salazar, M.; Wilkins, C.W., Jr.; Ryan, V.W.; Wang, T.T.; "Low-stress films of cyclized polybutadiene dielectrics by vacuum annealing"; Oct. 21-22, 1986; pp. 98-102.				
		Allen, Mark G.; Senturia, Stephan D.; "Measurement of polyimide interlayer adhesion using microfabricated structures"; 1988; pp. 352-356.				
		Kochugova, I.V.; Nikolaeva, L.V.; Vakser, N.M., (M.I. Kalinin Leningrad Polytechnic Institute (USSR)); "Electrophysical investigation of thin-layered inorganic coatings"; 1989; pp. 826-828.				

/TD/ 3/7/10

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant. *Applicant's unique citation designation number (see MPEP 609) ³See Kinds of USPTO Patent Documents at www.uspto.gov or MPEP 901.04. ⁴Entire Office that issued the document by the two-letter code (WIPO Standard ST.16) ⁵For Japanese documents, the name of the Japanese Patent Office or the name of the English translation precedes the surface code of the patent document. ⁶Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST.16 if possible. ⁷Applicant is to place a check mark here if English language Translation is attached.

Examiner Signature		Date Considered	
--------------------	---	-----------------	---